CLAIMS

What is claimed is:

L	1. A polish composition comprising abrasive particles and about 0.05 to about 5
2	% by weight of an anionic polyelectrolyte or a cationic polyelectrolyte.

- 2. The polish composition of claim 1 wherein the polyelectrolyte is an anionic polyelectrolyte.
- 3. The polish composition of claim 1 wherein the polyelectrolyte is a cationic electrolyte.
- 4. The polish composition of claim 1 wherein the polyelectrolyte has a molecular weight of less than about 100,000.
- 5. The polish composition of claim 1 wherein the polyelectrolyte has a molecular weight of about 300 to about 20,000.

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1	6. The polish composition of claim 1 wherein the polyelectrolyte is selected from		
2	the group consisting of poly (acrylic acid), poly (methacrylic acid), poly (methyl		
3	methacrylic acid), poly (maleic acid), and poly (vinylsulfonic acid).		
1	7. The polish composition of claim 1 wherein the polyelectrolyte is selected from		
2	the group consisting of poly (vinylamine), poly (ethylenimine) and poly (4-		
3	vinylpryridine).		
1	8. The polish composition of claim 1 wherein the polyelectrolyte is poly (acrylic		
2	acid).		
1 2	9. The polish composition of craim 1 wherein the polyelectrolyte is polyethylenimine.		
1	10. The polish composition of claim 1 wherein the abrasive particles comprise a		
2	member selected from the group consisting of ceria, alumina, silica and zirconia.		
1	11. The polish composition of claim 1 wherein the amount of the abrasive		
2	particles is about 0.1 to about 20 percent by weight.		

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12.	The polish composition of cl	laim being an aqueous slurry.
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13. A method for polishing a silicon dioxide surface in contact with a silicon nitride which comprises providing on the silicon dioxide surface a slurry comprising abrasive particles and an anionic polyelectrolyte in an amount sufficient to increase the polishing rate ratio of the silicon dioxide to the silicon nitride.

- 1 14. The method of claim 13 wherein the polyelectrolyte has a molecular weight of less than about 100,000.
 - 15. The method of claim 13 wherein the polyelectrolyte is selected from the groups consisting of poly (acrylic acid), poly (methacrylic acid), poly (methyl methacrylic acid), poly (maleic acid), and poly (vinylsulfonic acid).
- 1 16. The method of claim 13 wherein the polyelectrolyte is poly (acrylic acid).
- 1 17. The method of claim 13 wherein the amount of the abrasive particles is about 2 0.1 to about 20 percent by weight.

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1 Support 18. A method for polishing a metal surface which is in contact with at least one member selected from the group consisting of silicon dioxide, silicon nitride and silicon oxynitride which method comprises providing on the metal surface a slurry comprising abrasive particles and a cationic polyelectrolyte in an amount sufficient to increase the polishing rate ratio of the metal to said member.

- 19. The method of claim 18 wherein the polyelectrolyte is selected from the group consisting of poly (vinylamine), poly (ethylenimine), and poly (4- vinylpryridine).
- 20. The method of claim 18 wherein the polyelectrolyte is polyethylenimine.
 - 21. The method of claim 18 wherein the metal is W, Cu or Al.